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Substitu	ite for form 1449A/PTO			Complete if Known		
11.15	ODMATION		01 001105	Application Number	Not yet assigned	
INF	ORMATION I	JIS	CLOSURE	Filing Date	August 20, 2003	
STA	TEMENT BY	/ A	PPLICANT	First Named Inventor	Walton	
				Group Art Unit	Not yet assigned	
	(use as many sheet	s as	necessary)	Examiner Name	Not yet assigned	
Sheet	1	of	2	Attorney Docket Number	NC 84,613	

	U.S. PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	U.S. Patent Number	Cocument Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
		5,182,496		Manheimer et al	01/26/1993			
		5,874,807		Neger et al	02/23/1999			
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Examiner Initials*	Cite No.1	Foreign Patent Document Office ³ Number ⁴ Kind Code ⁵ (if known)				Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	16
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Examiner	Date	
Signature	Considered	

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.



^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Substitute for form 1449B/PTO			Co	Complet if Known		
			Application Number	Not yet assigned		
INFO	DRMATION	DISCLOSURE	Filing Date	August 20, 2003		
STATEMENT BY APPLICANT			First Named Inventor	Walton		
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	(use as many sh	eets as necessary)	Examiner Name	Not yet assigned		
Sheet	2	of 2	Attorney Docket Number	NC 84,613		

OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS								
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²					
	<u> </u>	MEGER et al, "Berned-Generated Plasmas for Processing Applications", Amer. Inst. of Physics, May 2001, Vol. 8 No. 5, pp. 2558-2564						
		LEONHARDT et al, "Plasma Diagnostic in Large area Plasma Processing System", Journal of Vacuum Science & Tech., July 2001, Vol. 19 No. 4, pp. 1367-1373						
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Examine Signature		Date Considered						

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